

Test Report issued under the responsibility of:



IEC 60601-1					
Medical electrical equipment					
Part 1: General requirements for basic safety and essential performance					
Report Reference No	E309264-D1011-1-CB				
Date of issue	2015-7-2				
Total number of pages:	256				
CB Testing Laboratory	UL Japan, Inc.				
Address	4383-326 Asama-cho, Ise-shi, Mie, 516-0021, Japan				
Applicant's name:	TDK-LAMBDA CORP				
Address	NAGAOKA TECHNICAL CENTER				
	R&D DIV 2704-1 SETTAYA-MACHI				
	NAGAOKA-SHI NIIGATA 940-1195 JAPAN				
Test specification:					
Standard	IEC 60601-1: 2005 + CORR. 1:2006 + CORR. 2:2007 + AM1:2012 (or IEC 60601-1: 2012 reprint)				
Test procedure:	CB Scheme				
Non-standard test method	N/A				
Test Report Form No	IEC60601_1J				
Test Report Form Originator:	UL(US)				
Master TRF	2014-07				

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The test results presented in this report relate only to the object tested.

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Trade Mark: Refer to Marking Label enclosure Manufacturer: Same as Applicant Model/Type reference: Models HWS1000L-X /YYYYYY, SWS1000L-X /YYYYYY, where X can be 3, 5, 12, 15, 24, 36, 48, or 60; and /YYYYYYY, oa be /RF; /RFHC, /RFCO2, /LLF, /LLFCO2, /BATz (z = blank or 3 digit max which consist of 0 to 9 and/or A to Z / BATz (z = blank or 3 digit max which consist of 0 to 9 and/or A to Z / BATz (z = blank or 3 digit max which consist of 0 to 9 and/or A to Z / BATz (z = blank or 3 digit max which consist of 0 to 9 and/or A to Z / BATz (z = blank or 3 digit max which consist of 0 to 9 and/or A to Z / BATz (z = blank or 3 digit max which consist of 0 to 9 and/or A to Z / BATz (z = blank or 3 digit max which consist of 0 to 9 and/or A to Z / BATz (z = blank or 3 digit max which consist of 0 to 9 and/or A to Z / BATz (z = blank or 3 digit max which consist of 0 to 9 and/or A to Z / BATz (z = blank or 3 digit max which consist of 0 to 9 and/or A to Z / BATz (z = blank or 3 digit max which consist of 0 to 9 and/or A to Z / BATz (z = blank or 3 digit max which consist of 0 to 9 and/or A to Z / BATz (z = blank or 3 digit max which consist of 0 to 9 and/or A to Z / BATz (z = blank or 3 digit max which consist of 0 to 9 and/or A to Z / BATZ (z = blank or 3) ////////////////////////////////////	Test item description:	Built in	Power Supply	
Manufacturer: Same as Applicant Model/Type reference: Models HWS1000L-X /YYYYYY, SWS1000L-X /YYYYYY, where X can be 3, 5, 12, 15, 24, 36, 48, or 60; and /YYYYYYY can be /RF, /RFHC /RFC02, /AC2, /RFL/LFC022, /ALF, /LE/C02, /BAT2 (z = blank, or 3 digit max which consist of 0 to 9 and/or A to Z) or blank. Ratings: Input: 100-240 VAC, 50/60 Hz, 13 A Outputs: HWS1000L-5, SWS1000L-3; 3.3 Vdc, 200 A HWS1000L-15, SWS1000L-12; 12 Vdc, max. 200 A (4-6 Vdc, max. 200 A and 1000 W) HWS1000L-12, SWS1000L-15; 15 Vdc, max. 70 A (12-19.5 Vdc, max. 70 A and 1056 W) HWS1000L-24; SWS1000L-15; 15 Vdc, max. 70 A (12-19.5 Vdc, max. 70 A and 1056 W) HWS1000L-24, SWS1000L-24; 24 Vdc, max. 29 A (28.8-43.2 Vdc, max. 29 A and 1056 W) HWS1000L-36; SWS1000L-36; 36 Vdc, max. 22 A (38.4-56 Vdc, max. 17 A and 1056 W) HWS1000L-60, SWS1000L-60; 60 Vdc, max. 17 A (48-66 Vdc, max. 17 A and 1026 W) HWS1000L-60; SWS1000L-60; 60 Vdc, max. 17 A (48-66 Vdc, max. 17 A and 1026 W) NOTE: Ratings in the parentheses are for reference only. These are not indicated on the device rating label. Testing location: [X] CB Testing Laboratory: It Japan, Inc. 4383-326 Asama-cho, Ise-shi, Mie, 516-0021, Japan [] Associated CB Testing Laboratory: It Japan, Inc. 4383-326 Asama-cho, Ise-shi, Mie, 516-0021, Japan [] Testing location/ address: It Jun Orito Jun Orito It store with with mathe signature): Jun Orito Jun Dut/Dub	·			
Model/Type reference: Models HWS1000L-X /YYYYYY, SWS1000L-X /YYYYYY, where X can be 3, 5, 12, 15, 24, 36, 48, or 60; and /YYYYYY can be /RF, /RFHC, /RFHC, /RFC02, /HC, /HCC02, /CD2, /RFHCC02, /LLF, /LLFC02, /BATZ (z = blank which consist of 0 to 9 and/or A to Z) or blank. Ratings: Input: 100-240 VAC, 50/60 Hz, 13 A Outputs: - HWS1000L-3; SWS1000L-3; 3.3 Vdc, 200 A - HWS1000L-12; 5 Vdc, max. 200 A (4-6 Vdc, max. 200 A and 1000 W) - HWS1000L-12; SWS1000L-12; 12 Vdc, max. 88 A (9.6-14.4 Vdc, max. 70 A and 1056 W) - HWS1000L-12; SWS1000L-12; 12 Vdc, max. 70 A (12-19.5 Vdc, max. 70 A and 1056 W) - HWS1000L-24; SWS1000L-15; 15 Vdc, max. 70 A (12-19.5 Vdc, max. 70 A and 1056 W) - HWS1000L-24; SWS1000L-24; 24 Vdc, max. 29 A (28.8-43.2 Vdc, max. 29 A and 1056 W) - HWS1000L-36; SWS1000L-48; 48 Vdc, max. 22 A (38.4-56 Vdc, max. 22 A and 1056 W) - HWS1000L-48; SWS1000L-48; 48 Vdc, max. 22 A (38.4-56 Vdc, max. 22 A and 1056 W) - HWS1000L-60; SWS1000L-60; 60 Vdc, max. 17 A (48-66 Vdc, max. 22 A and 1056 W) - HWS1000L-60; 60 Vdc, max. 17 A (48-66 Vdc, max. 17 A and 1020 W) NOTE: Ratings in the parentheses are for reference only. These are not indicated on the device rating label. Testing location/ address: UL Japan, Inc. 4383-326 Asama-cho, Ise-shi, Mie, 516-0021, Japan Testing location/ address: Testing location/ address: Jun Orito Jun Orito Jun Orito In Testing procedure: TMP/CTF Stage 1: Jun Orito Jun Dutio Jun Dutio			-	
X can be 3, 5, 12, 15, 24, 36, 48, or 60; and //YYYYYY can be //RF, //RFHC, //RFC02, //C2, //C2, //C2, //C2, //LC2, //LC2, //LC4, //LCC02, //LC4, //LC402, //L402, //L402, //L402, //L402, //L402, //L4		Currie		
Ratings: Input: 100-240 VAC, 50/60 Hz, 13 A Outputs: - HWS1000L-3; 3.3 Vdc, 200 A - HWS1000L-5; SWS1000L-5; S Vdc, max. 200 A (4-6 Vdc, max. 200 A and 1000 W) - HWS1000L-12; NSV1000L-12; 12 Vdc, max. 88 A (9.6-14.4 Vdc, max. 88 A and 1056 W) - HWS1000L-12, SWS1000L-15; 15 Vdc, max. 70 A (12-19.5 Vdc, max. 70 A and 1056 W) - HWS1000L-24; SWS1000L-24; 24 Vdc, max. 44 A (19.2-28.8 Vdc, max. 29 A and 1056 W) - HWS1000L-24, SWS1000L-36; 36 Vdc, max. 29 A (28.8-43.2 Vdc, max. 29 A and 1044 W) - HWS1000L-48; SWS1000L-48; 48 Vdc, max. 22 A (38.4-56 Vdc, max. 22 A and 1056 W) - HWS1000L-40; SWS1000L-60; 60 Vdc, max. 17 A (48-66 Vdc, max. 22 A and 1020 W) NOTE: Ratings in the parentheses are for reference only. These are not indicated on the device rating label. Testing procedure and testing location: [X] CB Testing Laboratory: [X] CB Testing Laboratory:	Model/Type reference:	X can be 3, 5, 12, 15, 24, 36, 48, or 60; and /YYYYYYY can be /RF, /RFHC, /RFCO2, /HC, /HCCO2, /CO2, /RFHCCO2, /LLF, /LLFCO2, /BATz (z = blank or 3 digit max which consist of 0 to 9 and/or A to Z		
- HWS1000L-3, SWS1000L-3; 3.3 Vdc, 200 A - HWS1000L-5, 5 Vdc, max. 200 A (4-6 Vdc, max. 200 A and 1000 W) - HWS1000L-12, SWS1000L-12; 12 Vdc, max. 88 A (9.6-14.4 Vdc, max. 88 A and 1056 W) - HWS1000L-15, SWS1000L-15; 15 Vdc, max. 70 A (12-19.5 Vdc, max. 70 A and 1050 W) - HWS1000L-24, SWS1000L-36; 36 Vdc, max. 29 A (28.8-43.2 Vdc, max. 44 A and 1056 W) - HWS1000L-36, SWS1000L-36; 36 Vdc, max. 29 A (28.8-43.2 Vdc, max. 29 A and 1044 W) - HWS1000L-60, SWS1000L-60; 60 Vdc, max. 17 A (48-66 Vdc, max. 21 A and 1056 W) - HWS1000L-60, SWS1000L-60; 60 Vdc, max. 17 A (48-66 Vdc, max. 17 A and 1020 W) NOTE: Ratings in the parentheses are for reference only. These are not indicated on the device rating label. Testing procedure and testing location: [X] CB Testing Laboratory: Testing location/ address: UL Japan, Inc. 4383-326 Asama-cho, Ise-shi, Mie, 516-0021, Japan [] Associated CB Testing Laboratory: Testing location/ address: Tested by (name + signature): Jun Orito Jun Orito Approved by (name + signature): Tsutomu Abe [] Testing procedure: TMP/CTF Stage 1:	Ratings:	İnput: 100-240 VAC, 50/60 Hz, 13 A		
- HWS1000L-5, SWS1000L-5; 5 Vdc, max. 200 A (4-6 Vdc, max. 200 A and 1000 W) - HWS1000L-12, SWS1000L-12; 12 Vdc, max. 88 A (9.6-14.4 Vdc, max. 88 A and 1056 W) - HWS1000L-15, SWS1000L-15; 15 Vdc, max. 70 A (12-19.5 Vdc, max. 70 A and 1050 W) - HWS1000L-24, SWS1000L-36; 36 Vdc, max. 44 A (19.2-28.8 Vdc, max. 44 A and 1056 W) - HWS1000L-36, SWS1000L-36; 36 Vdc, max. 29 A (28.8-43.2 Vdc, max. 44 A and 1056 W) - HWS1000L-48, SWS1000L-36; 36 Vdc, max. 29 A (28.8-43.2 Vdc, max. 22 A and 1044 W) - HWS1000L-48, SWS1000L-36; 36 Vdc, max. 22 A (38.4-56 Vdc, max. 22 A and 1056 W) - HWS1000L-60, SWS1000L-60; 60 Vdc, max. 17 A (48-66 Vdc, max. 17 A and 1020 W) NOTE: Ratings in the parentheses are for reference only. These are not indicated on the device rating label. Testing procedure and testing location: [X] CB Testing Laboratory: Testing location/ address: UL Japan, Inc. 4383-326 Asama-cho, Ise-shi, Mie, 516-0021, Japan [] Associated CB Testing Laboratory: Testing location/ address: Jun Orito Approved by (name + signature): Jun Orito Approved by (name + signature): Tsutomu Abe [] Testing procedure: TMP/CTF Stage 1:				dc. 200 A
- HWS1000L-12, SWS1000L-12; 12 Vdc, max. 88 A (9.6-14.4 Vdc, max. 88 A and 1056 W) - HWS1000L-24, SWS1000L-15; 15 Vdc, max. 70 A (12-19.5 Vdc, max. 70 A and 1050 W) - HWS1000L-24, SWS1000L-24; 24 Vdc, max. 44 A (19.2-28.8 Vdc, max. 44 A and 1056 W) - HWS1000L-36; 36 Vdc, max. 29 A (28.8-43.2 Vdc, max. 29 A and 1056 W) - HWS1000L-48, SWS1000L-48; 48 Vdc, max. 29 A (28.8-43.2 Vdc, max. 29 A and 1044 W) - HWS1000L-48, SWS1000L-48; 48 Vdc, max. 22 A (38.4-56 Vdc, max. 22 A and 1056 W) - HWS1000L-60; SWS1000L-60; 60 Vdc, max. 17 A (48-66 Vdc, max. 17 A and 1020 W) NOTE: Ratings in the parentheses are for reference only. These are not indicated on the device rating label. Testing procedure and testing location: [X] CB Testing Laboratory: Testing location/ address: UL Japan, Inc. 4383-326 Asama-cho, Ise-shi, Mie, 516-0021, Japan [] Associated CB Testing Laboratory: Testing location/ address: Tested by (name + signature): Jun Orito Approved by (name + signature): Testing procedure: TMP/CTF Stage 1;		- HWS1000L-5, SWS1000L-5; 5 Vdc, max. 200 A (4-6 Vdc, max.		
- HWS1000L-15, SWS1000L-15; 15 Vdc, max. 70 A (12-19.5 Vdc, max. 70 A and 1050 W) - HWS1000L-24, SWS1000L-24; 24 Vdc, max. 44 A (19.2-28.8 Vdc, max. 44 A and 1056 W) - HWS1000L-36, SWS1000L-36; 36 Vdc, max. 29 A (28.8-43.2 Vdc, max. 29 A and 1044 W) - HWS1000L-48, SWS1000L-48; 48 Vdc, max. 22 A (38.4-56 Vdc, max. 22 A and 1056 W) - HWS1000L-60, SWS1000L-60; 60 Vdc, max. 17 A (48-66 Vdc, max. 17 A and 1020 W) NOTE: Ratings in the parentheses are for reference only. These are not indicated on the device rating label. Testing procedure and testing location: [X] CB Testing Laboratory: Testing location/ address: UL Japan, Inc. 4383-326 Asama-cho, Ise-shi, Mie, 516-0021, Japan [] Associated CB Testing Laboratory: Tested by (name + signature): Jun Orito Approved by (name + signature): Tsutomu Abe [] Testing procedure: TMP/CTF Stage 1:		- HWS	1000L-12, SWS1000L-12; 12 Vdc, max. 88 A (9.6-14.4 Vdc,	
- HWS1000L-24, SWS1000L-24; 24 Vdc, max. 44 A (19.2-28.8 Vdc, max. 44 A and 1056 W) - HWS1000L-36; SWS1000L-36; 36 Vdc, max. 29 A (28.8-43.2 Vdc, max. 29 A and 1054 W) - HWS1000L-48, SWS1000L-48; 48 Vdc, max. 22 A (38.4-56 Vdc, max. 22 A and 1056 W) - HWS1000L-60; SWS1000L-60; 60 Vdc, max. 17 A (48-66 Vdc, max. 17 A and 1020 W) NOTE: Ratings in the parentheses are for reference only. These are not indicated on the device rating label. Testing procedure and testing location: [X] CB Testing Laboratory: Testing location/ address: UL Japan, Inc. 4383-326 Asama-cho, Ise-shi, Mie, 516-0021, Japan [] Associated CB Testing Laboratory: Testing location/ address: Jun Orito Approved by (name + signature): Jun Orito Approved by (name + signature): Tsutomu Abe [] Testing procedure: TMP/CTF Stage 1:		- HWS1000L-15, SWS1000L-15; 15 Vdc, max. 70 A (12-19.5 Vdc, max. 70 A and 1050 W) - HWS1000L-24, SWS1000L-24; 24 Vdc, max. 44 A (19.2-28.8 Vdc,		
- HWS1000L-36, SWS1000L-36; 36 Vdc, max. 29 A (28.8-43.2 Vdc, max. 29 A and 1044 W) - HWS1000L-48, SWS1000L-48; 48 Vdc, max. 22 A (38.4-56 Vdc, max. 22 A and 1056 W) - HWS1000L-60, SWS1000L-60; 60 Vdc, max. 17 A (48-66 Vdc, max. 17 A and 1020 W) NOTE: Ratings in the parentheses are for reference only. These are not indicated on the device rating label. Testing procedure and testing location: [X] CB Testing Laboratory: Testing location/ address: UL Japan, Inc. 4383-326 Asama-cho, Ise-shi, Mie, 516-0021, Japan [] Associated CB Testing Laboratory: Testing location/ address: Jun Orito Approved by (name + signature): Jun Orito Approved by (name + signature): Testing procedure: TMP/CTF Stage 1:				Vdc, max. 44 A (19.2-28.8 Vdc,
- HWS1000L-48, SWS1000L-48, 48 Vdc, max. 22 A (38.4-56 Vdc, max. 22 A and 1056 W) - HWS1000L-60, SWS1000L-60; 60 Vdc, max. 17 A (48-66 Vdc, max. 17 A and 1020 W) NOTE: Ratings in the parentheses are for reference only. These are not indicated on the device rating label. Testing procedure and testing location: [X] CB Testing Laboratory: Testing location/ address: UL Japan, Inc. 4383-326 Asama-cho, Ise-shi, Mie, 516-0021, Japan [] Associated CB Testing Laboratory: Tested by (name + signature): Jun Orito Approved by (name + signature): Testing procedure: TMP/CTF Stage 1:		- HWS	1000L-36, SWS1000L-36; 36	Vdc, max. 29 A (28.8-43.2 Vdc,
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NOTE: Ratings in the parentheses are for reference only. These are not indicated on the device rating label. Testing procedure and testing location: [X] CB Testing Laboratory: Testing location/ address: [] Associated CB Testing Laboratory: Testing location/ address: Tested by (name + signature): Jun Orito Approved by (name + signature): Testing procedure: TMP/CTF Stage 1:				Vdc, max. 17 A (48-66 Vdc,
not indicated on the device rating label. Testing procedure and testing location: [X] CB Testing Laboratory: Testing location/ address: UL Japan, Inc. 4383-326 Asama-cho, Ise-shi, Mie, 516-0021, Japan [] Associated CB Testing Laboratory: Testing location/ address: Image: Colspan="2">Testing location/ address: Tested by (name + signature): Jun Orito Jun Dumb Approved by (name + signature): Tsutomu Abe Image: Colspan="2">Image: Colspan="2">Image: Colspan="2">Testing procedure: TMP/CTF Stage 1:		max. 1	7 A and 1020 W)	
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[X] CB Testing Laboratory: UL Japan, Inc. Testing location/ address: UL Japan, Inc. [] Associated CB Testing Laboratory: Hermitian Testing location/ address: Tested by (name + signature): Jun Orito Jun Orito Approved by (name + signature): Tsutomu Abe [] Testing procedure: TMP/CTF Stage 1: Image: Testing Procedure: TMP/CTF Stage 1:		The find	indica on the across rating lab	
Testing location/ address: UL Japan, Inc. 4383-326 Asama-cho, Ise-shi, Mie, 516-0021, Japan [] Associated CB Testing Laboratory: Testing location/ address: Testing location/ address: Jun Orito Tested by (name + signature): Jun Orito Approved by (name + signature): Tsutomu Abe [] Testing procedure: TMP/CTF Stage 1: Image: TMP/CTF Stage 1:	Testing procedure and testing location	า:	1	
4383-326 Asama-cho, Ise-shi, Mie, 516-0021, Japan [] Associated CB Testing Laboratory: Testing location/ address: Tested by (name + signature): Jun Orito Approved by (name + signature): Tsutomu Abe [] Testing procedure: TMP/CTF Stage 1:	[X] CB Testing Laboratory:			
[] Associated CB Testing Laboratory: Testing location/ address: Tested by (name + signature): Jun Orito Approved by (name + signature): Tsutomu Abe I] Testing procedure: TMP/CTF Stage 1:	Testing location/ address:		UL Japan, Inc.	
Testing location/ address:			4383-326 Asama-cho, Ise-shi, Mie, 516-0021, Japan	
Tested by (name + signature): Jun Orito Jun Duito Approved by (name + signature): Tsutomu Abe Jun Duito [] Testing procedure: TMP/CTF Stage 1: Image: TMP/CTF Stage 1: Image: TMP/CTF Stage 1:	[] Associated CB Testing Laborate	ory:		
Approved by (name + signature): Tsutomu Abe [] Testing procedure: TMP/CTF Stage 1:	Testing location/ address:			
[] Testing procedure: TMP/CTF Stage 1:	Tested by (name + signature):		Jun Orito	Jun Dungs
[] Testing procedure: TMP/CTF Stage 1:	Approved by (name + signature).		Tsutomu Abe	L.
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Testing location/ address:	[] Testing procedure: TMP/CTF S	tage 1:		
	Testing location/ address:			

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Report No.: E309264-D1011-1-CB

Tested by (name + signature):	
Approved by (name + signature):	
[] Testing procedure: WMT/CTF Stage 2:	
Testing location/ address:	
Tested by (name + signature):	
Witnessed by (name + signature):	
Approved by (name + signature):	
[] Testing procedure: SMT/CTF Stage 3 or 4:	
Testing location/ address:	
Tested by (name + signature):	
Witnessed by (name + signature):	
Approved by (name + signature):	
Supervised by (name + signature):	

List of Attachments (including a total number of pages in each attachment):					
Refer to Appendix A of this report. All attachments are included within this report.					
Summary of testing					
Tests performed (name of test and test clause):	Testing location:				
Refer to the Test List in Appendix B of this report if testing was performed as part of this evaluation.					
Summary of compliance with National Differences					
List of countries addressed: Austria, USA, Canada, United Kingo	dom, Sweden				

Copy of marking plate

The artwork below may be only a draft. The use of certification marks on a product must be authorized by the respective NCBs that own these marks.

Refer to the enclosure(s) titled Marking Plate in the Enclosures section in Appendix A of this report for a copy.